Special Issue

Advanced EUV and X-Ray Optics

Message from the Guest Editors

More than a century after the discovery of X-ray radiation by Wilhelm Conrad Röntgen in 1895, short wavelength radiation in the extreme ultraviolet to soft X-ray region of the electromagnetic spectrum has been developed into an inevitable and unique probe for fundamental research in physics, chemistry, astronomy and life sciences, as well as a driver of technological development, e.g., in advanced microscopy and lithography systems. This Special Issue of the journal *Applied Sciences* "Advanced EUV and X-Ray Optics" calls for research articles covering such new ideas and recent advances in the design, development, fabrication and application of EUV and/or soft X-ray optical elements and systems with unprecedented parameters.
Keywords: ultrafast optics; chirping; pulse shaping; multilayer mirrors; diffractive optics; design and fabrication of multilayer optics; optimization of multilayer optics; EUV and soft X-rays; metrology of multilayer optics; lithography optics; polarizers; FEL optics

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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